APT30DQ120BG Datasheet Ultrafast Soft Recovery Rectifier Diode

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1 Revision History

The revision history describes the changes that were implemented in the document. The changes are listed by revision, starting with the most current publication.

1.1 Revision D

Revision D was published in March 2018. The following is a summary of the changes in revision D of this document.

- The new Microsemi template and format was applied.
- The lead thicknesses and spacing was updated. See Package Outline Drawing.

1.2 Revision C

Revision C was published in May 2011. The following is a summary of the changes in revision C of this document.

- The patent information was removed from the document.
- For TO-247 packages: the maximum lead thickness was changed from 0.70 in (0.031 mm) to 1.016 in (0.040 mm).

1.3 Revision B

Revision B was published in July 2009. The following is a summary of the changes in revision B of this document.

• New graphs were added to the document. See Typical Performance Curves.

1.4 Revision A

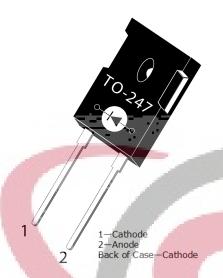
Revision A was published in February 2006. It is the first publication of this document.





2 Product Overview

This section shows the product overview for the APT30DQ120BG device.



2.1 Features

The following are key features of the APT30DQ120BG device:

- Ultrafast recovery times
- Soft recovery characteristics
- Low forward voltage
- Low leakage current
- Avalanche energy rated
- RoHS compliant
- AEC-Q101 qualified

2.2 Benefits

The following are benefits of the APT30DQ120BG device:

- High switching frequency
- Low switching losses
- Low noise (EMI) switching
- Higher reliability systems
- Increased system power density

2.3 Applications

The APT30DQ120BG device is designed for the following applications:

- Power factor correction (PFC)
- Anti-parallel diode
 - Switch-mode power supply
 - Inverters/converters
 - Motor controllers
- Freewheeling diode
 - Switch-mode power supply
 - Inverters/converters
- Snubber/clamp diode





3 Electrical Specifications

This section shows the electrical specifications for the APT30DQ120BG device.

3.1 Absolute Maximum Ratings

The following table shows the absolute maximum ratings for the APT30DQ120BG device.

All ratings: Tc = 25 °C unless otherwise specified.

Table 1 • Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
VR	Maximum DC reverse voltage	1200	V
VRRM	Maximum peak repetitive reverse voltage	1200	
V _{RWM}	Maximum working peak reverse voltage	1200	
IF(AV)	Maximum average forward current (Tc = 117 °C, duty cycle = 0.5)	30	Α
IF(RMS)	RMS forward current	43	
IFSM	Non-repetitive forward surge current (T _J = 45 °C, 8.3 ms)	210	
EAVL	Avalanche ener <mark>gy (1 A, 40</mark> mH)	20	mJ
Тл, Тѕтб	Operating and storage temperature range	-55 to 175	°C
Τι	Lead temperature for 10 seconds	300	

3.2 Electrical Performance

The following table shows the static electrical characteristics of the APT30DQ120BG device.

Table 2 • Static Electrical Characteristics

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
VF	Forward voltage	I _F = 30 A		2.8	3.3	V
1		I _F = 60 A		3.4		-
		I _F = 30 A, T _J = 125 °C		2.1		=
Irm	Maximum reverse leakage current	V _R = 1200 V			100	μΑ
-		V _R = 1200 V, T _J = 125 °C		N.	500	=
Ст	Junction capacitance	V _R = 200 V		36		pF





The following table shows the dynamic characteristics of the APT30DQ120BG device.

Table 3 • Dynamic Characteristics

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
trr	Reverse recovery time	I _F = 1 A		26		ns
		$di_F/dt = -100 A/\mu s$				
		$V_R = 30 \text{ V}$				
		Tc = 25 °C				
trr	Reverse recovery time	I _F = 30 A		320		-
Qrr	Reverse recovery charge	di _F /dt = -200 A/μs V _R = 800 V		545		nC
IRRM	Maximum reverse recovery current	Tc = 25 °C		4		Α
trr	Reverse recovery time	I _F = 30 A	1	435		ns
Qrr	Reverse recovery charge	di _F /dt = -200 A/μs V _R = 800 V	11	2100		nC
IRRM	Maximum reverse recovery current	Tc = 125 °C		9		Α
trr	Reverse recovery time	I _F = 30 A	9	180		ns
Qrr	Reverse recovery charge	di _F /dt = -1000 A/μs V _R = 800 V		2975		nC
IRRM	Maximum reverse recovery current	Tc = 125 °C		28		Α

The following table shows the thermal and mechanical characteristics of the APT30DQ120BG device.

Table 4 • Thermal and Mechanical Characteristics

Symbol	Characteristic	Min	Тур	Max	Unit
Reлc	Junction-to-case thermal resistance		7	0.80	°C/W
WT	Package weight	7 10	0.22		oz
		4	5.9		g
Torque	Maximum mounting torque			10	lb∙m
- /		7		1.1	N∙m





3.3 Typical Performance Curves

This section shows the typical performance curves for the APT30DQ120BG device.

Figure 1 • Maximum Effective Transient Thermal Impedance, Junction-to-Case vs. Pulse

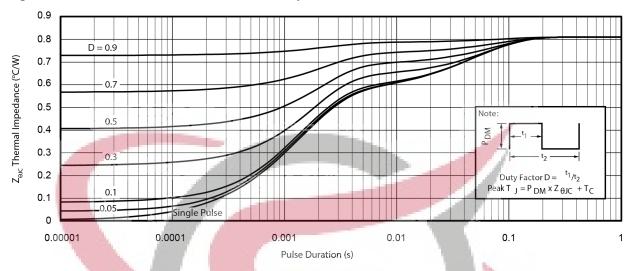


Figure 2 • Forward Current vs. Forward Voltage

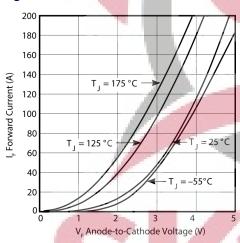
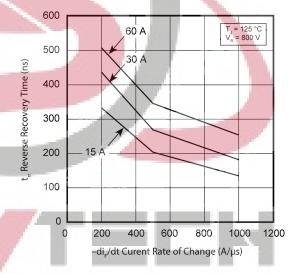


Figure 3 • RRT vs. Current Rate of Change



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Figure 4 • RRC vs. Current Rate of Change

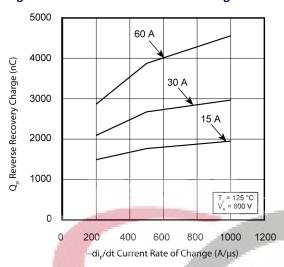


Figure 6 • Dynamic Parameters vs. Junction
Temperature

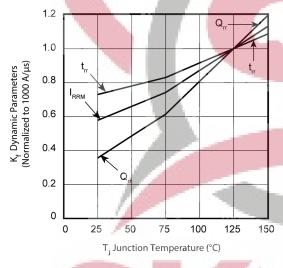


Figure 8 • Junction Capacitance vs. Reverse Voltage

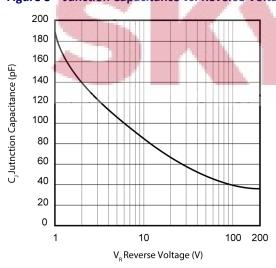


Figure 5 • RRC vs. Current Rate of Change

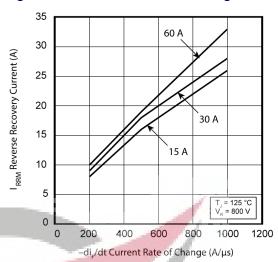
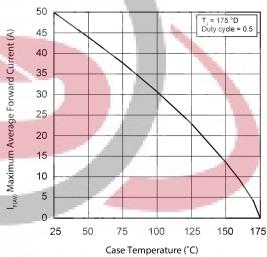


Figure 7 • Maximum Average Forward Current vs. Case Temperature



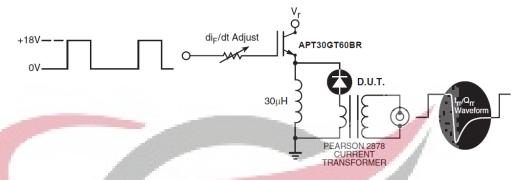




3.4 Reverse Recovery Overview

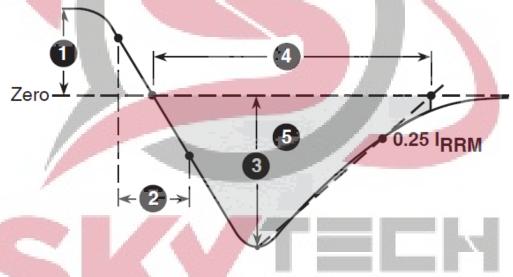
The following illustration shows the reverse recovery testing and measurement information for the APT30DQ120BG device.

Figure 9 • Diode Test Circuit



The following illustration shows the diode reverse recovery waveform and definitions for the APT30DQ120BG device.

Figure 10 • Diode Reverse Recovery Waveform and Definitions



- 1. IF—Forward conduction current.
- 2. dif/dt—Rate of diode current change through zero crossing.
- 3. IRRM—Maximum reverse recovery current.
- 4. t_{rr}—Reverse recovery time, measured from zero crossing where diode current goes from positive to negative, to the point at which the straight line through IRRM and 0.25 IRRM passes through zero.
- 5. $Q_{\text{rr}}\text{--}Area under the curve defined by <math display="inline">I_{\text{RRM}}$ and $t_{\text{rr}}.$



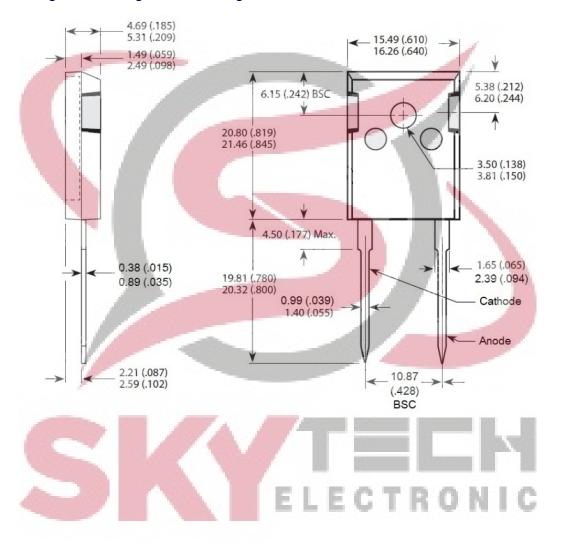
4 Package Specification

This section shows the package specification for the APT30DQ120BG device.

4.1 Package Outline Drawing

This section details the TO-247 package drawing of the APT30DQ120BG device. Dimensions are in millimeters and (inches).

Figure 11 • Package Outline Drawing











Power Matters."

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